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Substitute for form 1449A/B/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)		Complete if Known			
		Application Number	10/672,961 (Conf. No. 9439)		
		Filing Date	September 26, 2003		
		First Named Inventor	Glenn J. Leedy		
		Art Unit	2822		
Examiner Name	Monica Lewis				
Sheet	1	of	2	Attorney Docket Number	ELM-2 Cont. 4

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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Examiner Initials*	Cite No. ¹	Foreign Patent Document Country Code ² -Number ³ -Kind Code ⁴ (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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		WO 98/40337	05-07-1998	Trusi Technologies, LLC	

Examiner Signature		Date Considered	1/11/07
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Sheet	2	of	2	Attorney Docket Number	ELM-2 Cont. 4

NON PATENT LITERATURE DOCUMENTS				
Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²	
		Wolf, Stanley and Richard N. Tauber: <u>Silicon Processing For the VLSI Era, Volume 1: Process Technology</u> ; Sunset Beach, CA: Lattice Press, 1986, pages 191-194		
		European Search Report for Application No. EP-02-00-9643 (date completed: October 8, 2002)		
		Phys. Rev. B., <u>Condens. Matter Mater. Phys. (USA)</u> , Physical Review B (Condensed Matter and Materials Physics), 15 March 2003, APS through AIP, USA.		
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		Svechnikov, S.V.; Kobylitskaya, M.F.; Kimarskii, V.I.; Kaufman, A.P.; Kuzolev, Yu. I.; Cherepov, Ye. I.; Fomin, B.I.; "A switching plate with aluminium membrane crossings of conductors"; 1972		
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Examiner Signature		Date Considered	11/10/03
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